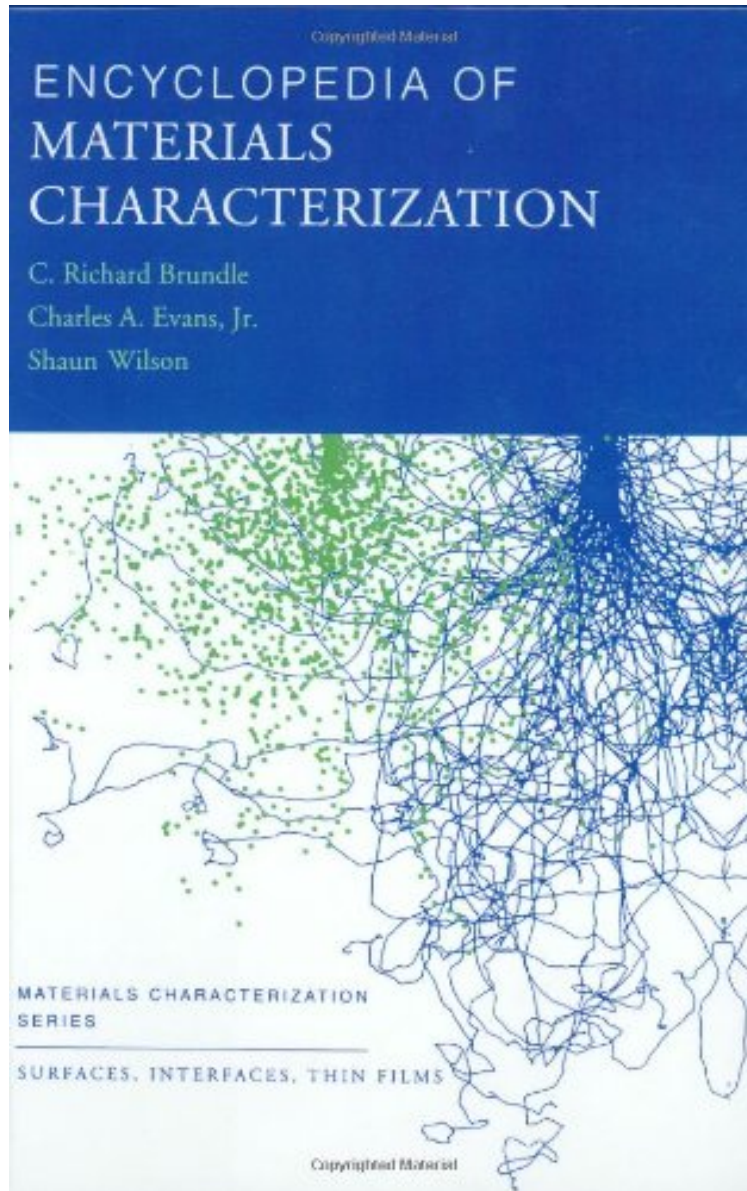


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## Encyclopedia of Materials Characterization: Surfaces, Interfaces, Thin Films (Materials Characterization Series)

*Charles Evans, Richard Brundle, Wilson*  
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